

**Search Notes**

Application/Control No.

10/601,815

Examiner

Christian A. Hannon

Applicant(s)/Patent under  
Reexamination

ECKL ET AL.

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
455	180.2	8/9/06	CH
1	180.4	1	1
331	177v	1	1

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
455	180.4	8/9/06	CH
455	180.2	8/9/06	1
331	177v	8/9/06	1
PGPUB TEXT SEARCH		8/9/06	CH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
consulted w/ Q. Vuong Updated search	8/9/06	CH